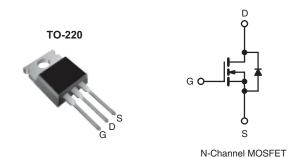




Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	450			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	1.2		
Q _g (Max.) (nC)	45			
Q _{gs} (nC)	6.6			
Q _{gd} (nC)	24			
Configuration	Single			



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free



COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION			
Package	TO-220		
Lead (Pb)-free	IRF734PbF		
	SiHF734-E3		

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, u	nless otherw	ise noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	450	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V -+ 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$		4.9	А	
	V _{GS} at 10 V	T _C = 100 °C	I _D	3.1		
Pulsed Drain Current ^a			I _{DM}	20		
Linear Derating Factor				0.59	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	330	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4.9	Α	
Repetitive Avalanche Energy ^a			E _{AR}	7.4	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	74	W	
Peak Diode Recovery dV/dt ^c			dV/dt	4.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	00	
Soldering Recommendations (Peak Temperature)	for 10 s		_	300 ^d	°C	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
			-	1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 24 \,^{\circ}\text{mH}$, $R_G = 25 \,^{\circ}\Omega$, $I_{AS} = 4.9 \,^{\circ}\Lambda$ (see fig. 12).
- c. $I_{SD} \le 4.9$ A, $dI/dt \le 80$ A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R_{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.7		

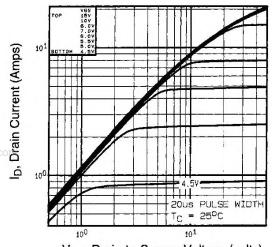
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		450	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.63	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	- 50	$V_{DS} = 450 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 360 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 ^{\circ}\text{C}$		-	25 250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.9 A ^b	-	-	1.2	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 5	50 V, I _D = 2.9 A ^b	3.0	-	-	S
Dynamic		1					
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz, see fig. 5}$		-	680	-	pF
Output Capacitance	C _{oss}			-	190	-	
Reverse Transfer Capacitance	C _{rss}			-	75	-	
Total Gate Charge	Q_g		I _D = 4.9 A, V _{DS} = 360 V - see fig. 6 and 13 ^b -	-	-	45	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V		-	-	6.6	
Gate-Drain Charge	Q _{gd}			-	-	24	
Turn-On Delay Time	t _{d(on)}	V_{DD} = 225 V, I_{D} = 4.9 A R_{G} = 12 Ω, R_{D} = 45 Ω, see fig. 10 ^b		-	5.9	-	ns
Rise Time	t _r			-	22	-	
Turn-Off Delay Time	t _{d(off)}			-	40	-	
Fall Time	t _f			-	21	-	
Internal Drain Inductance	L_{D}	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbo	MOSFET symbol showing the		-	4.9	Α
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		ı	-	20	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, \ I_S = 4.9 \text{A}, \ V_{GS} = 0 \text{V}^{\text{b}}$		-	-	2.0	٧
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 4.9 A, dl/dt = 100 A/μs ^b		-	460	690	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	μС
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S an				y L _S and	L _D)

Notes

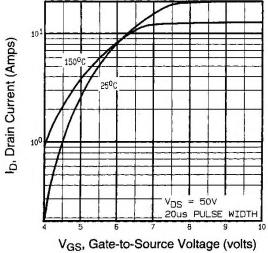
- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



 V_{DS} , Drain-to-Source Voltage (volts) Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C



V_{GS}, Gate-to-Source voltage (volts) Fig. 3 - Typical Transfer Characteristics

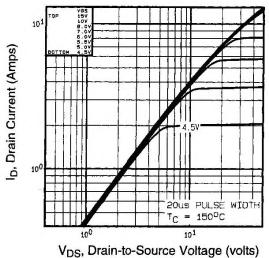


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

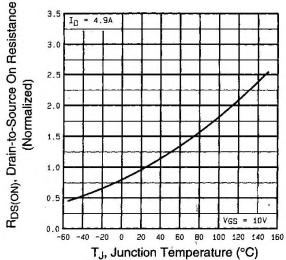


Fig. 4 - Normalized On-Resistance vs. Temperature

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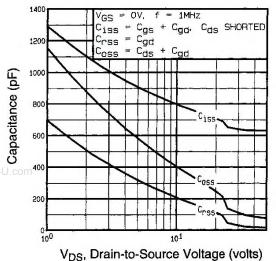


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

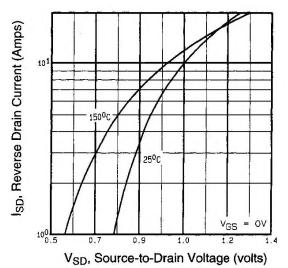
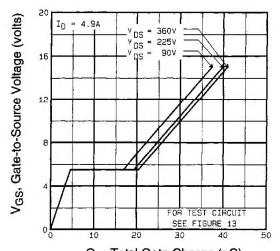


Fig. 7 - Typical Source-Drain Diode Forward Voltage



 $\label{eq:QG} Q_G, \mbox{ Total Gate Charge (nC)} \\ \mbox{Fig. 6 - Typical Gate Charge vs. Drain-to-Source Voltage}$

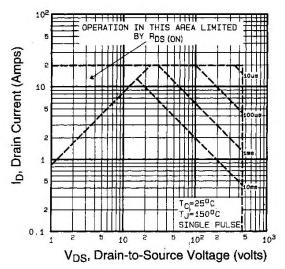


Fig. 8 - Maximum Safe Operating Area





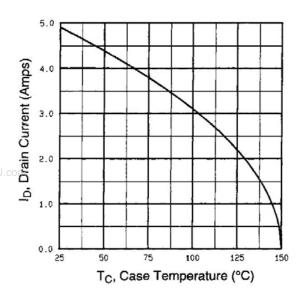


Fig. 9 - Maximum Drain Current vs. Case Temperature

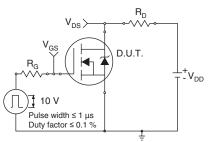


Fig. 10a - Switching Time Test Circuit

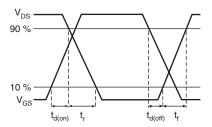


Fig. 10b - Switching Time Waveforms

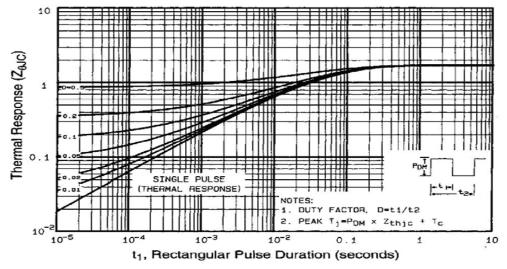


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

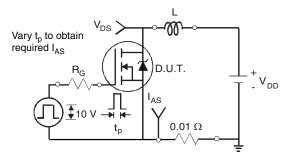


Fig. 12a - Unclamped Inductive Test Circuit

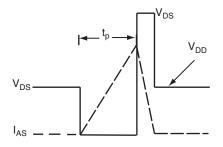


Fig. 12b - Unclamped Inductive Waveforms

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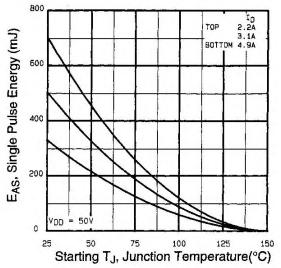


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

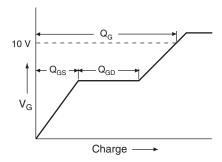


Fig. 13a - Basic Gate Charge Waveform

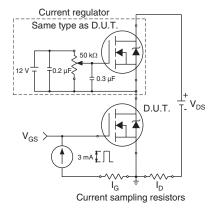
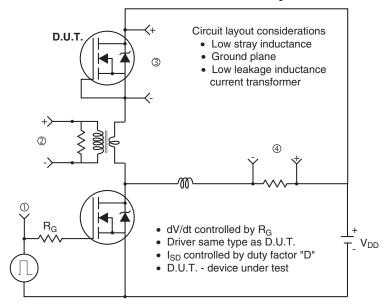


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



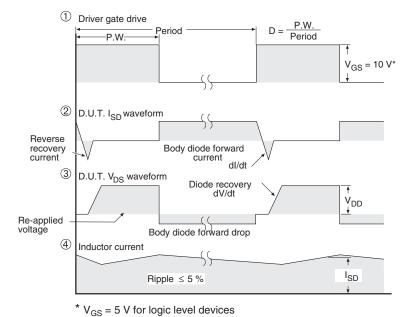


Fig. 14 - For N-Channel

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